

# **Title:** Giant Polarization in Super-Tetragonal Ferroelectric Thin Films through

### **Interphase Strain**

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**Abstract**: Strain engineering has emerged as a powerful tool to create new states of known materials with excellent performance. Here, we show a general and practically realizable method via interphase strain to obtain a new super tetragonality providing giant polarization. This method is illustrated for the case of PbTiO<sub>3</sub>, where we report a c/a ratio of up to 1.238 in epitaxial composite thin films, compared to that of 1.065 in bulk PbTiO<sub>3</sub>. These thin films of super-tetragonal structure possess an unprecedented giant remanent polarization, 236.3  $\mu$ C/cm<sup>2</sup>, which is almost twice the value of all known ferroelectrics. The tetragonal phase is stable up to 725 °C as compared to the bulk's transition temperature of 490 °C. The present interphase strain approach could provide a new avenue to enhance the physical properties of materials with respect to their multiferroic, photonic, superconductor, and energy-harvesting behavior.

### Main Text:

Strain offers a handle to enhance the properties of multifunctional materials (1-3), including magnetoresistance, superconductivity and ferroelectricity. For example, the critical temperature of the La<sub>1.9</sub>Sr<sub>0.1</sub>CuO<sub>4</sub> superconductor was raised from 25 K to 49.1 K using epitaxial strain (2). Another example concerns multiferroic BiFeO<sub>3</sub>, whereby a large biaxial compressive strain in films changed their rhombohedral phase into a super-tetragonal one. Significantly different ferroelectric and antiferromagnetic properties have been achieved (4). Among strained ferroelectrics (5-8), widely studied perovskite oxides appearing with giant tetragonality may have a large value of the polarization and a high Curie temperature ( $T_C$ ) as a consequence of their large dipolar moment (4,9-12), providing greatly added value for electronic device design. However, these compounds are rare and generally demand extreme synthesis conditions. One example of the synthetic approach to obtain such behavior is the expensive high compressive

pressure with diamond anvil cells (11,12), such as for preparation of PbVO<sub>3</sub> and BiCoO<sub>3</sub>. Another approach of using the particular biaxial strain imposed by lattice-mismatched substrates on films has been successfully applied in many cases (1,10,13,14). It is also possible to use isotropic strain to affect the structure and properties of materials (11,12,15-18). The  $T_{\rm C}$  of pulsed-laser deposition BaTiO<sub>3</sub> films can be controllably tuned to over 800 °C by the coupling between epitaxial strain and the isotropic strain provided by defect dipoles (16). In particular, it has been shown that isotropic tensile strain (negative pressure) theoretically increases tetragonality and polarization of perovskite oxides, such as BaTiO<sub>3</sub> and PbTiO<sub>3</sub> (fig. S1) (15). Experimentally, Wang et al. have successfully achieved a negative pressure in PbTiO<sub>3</sub> nanowires by taking advantage of the phase transformation induced stress to enhance physical properties (17,18). The isotropic strain is assuredly crucial for the design of materials; however, engineering such high negative pressure in experiments is regarded as a great challenge. A simpler practical approach for achieving the same effects as negative pressure is therefore desired, especially for epitaxial films.

Here, we investigate such concept, termed "interphase strain", to introduce large strain, in which two materials having similar crystal structure but different lattice parameters can be grown in a single epitaxial composite, so that the interfaces between them are matched coherently with similar lattice parameters. This is different to the conventional composite, in which different phases have their own lattice parameters. In this way an isotropic tensile or compression strain can be introduced into the material which originally had the smaller or larger lattice parameters, respectively. This strain is named interphase strain, and it can be expected to improve the structure and properties of functional materials. In this study this concept of interphase strain has been implemented to introduce a negative pressure in PbTiO<sub>3</sub> epitaxial composite ferroelectric

thin films via PbO. Our results feature a much larger polarization, c/a ratio, and stable temperature than any previous studies on PbTiO<sub>3</sub>.

The epitaxial composite films were grown on  $SrTiO_3$  (STO) substrates using a simple radiofrequency (rf) magnetron sputtering. The atomic deposition rate can be controlled by the oxygen ratio as discussed below. The samples of PT (I), and PT (II) were prepared without oxygen, and with 9 % oxygen, respectively. If either of PT (I) or PT (II) samples is annealed above 725°C, then a new atomic structure is obtained, classified as PI (III). Figure 1A highlights a small region (17° to 24°) of the general X-ray diffraction scans, demonstrating the apparent change in the *c* lattice parameters of PT (I), PT (II), and PT (III). Together with the results of high resolution Xray scans covering a large angle (15° to 75°) (fig. S2A), only diffraction peaks from the directions of (100) STO substrate and (001) films can be observed. It reveals that all films are epitaxial and have a single set of tetragonal lattice parameter. Additional phi scans of both (101) and (103) planes of PT (I) feature four-axis symmetric structure, confirming an in-plane epitaxial relationship (Fig. 1C).

The typical epitaxial PbTiO<sub>3</sub> films (PT (III)) reveal the normal *c* lattice parameter of ~4.08 Å that is established in the literature (*19*). In contrast, the primitive PT (I) and PT (II) grown on the same STO substrate exhibit strong reflections at anomalous values corresponding to *c* lattice parameters of ~4.408 Å and ~4.840 Å, respectively. Subsequent synchrotron-based X-ray reciprocal space mappings (RSM) about the (103) plane of the films and substrates (Fig. 1B) verify that the *a* axis is well matched between the substrates and the films, but the *c* axis of the films unveil a colossal difference. The position of the *c* axis of bulk PbTiO<sub>3</sub> is indicated by the dotted line for comparison, which is similar to that of the normal coherently strained PbTiO<sub>3</sub> thin films (PT (III)). Strikingly, an increase in the *c* axis is observed in PT (I) and PT (II) by 16.5 %

and 6.1 %, respectively, as compared to the bulk value (20). Furthermore, both c and c/a increase with increasing thickness of PT (I) or PT (II) (Fig. 1D), which indicates that the growth strain is weakly controlled by the substrate as discussed in Table S1.

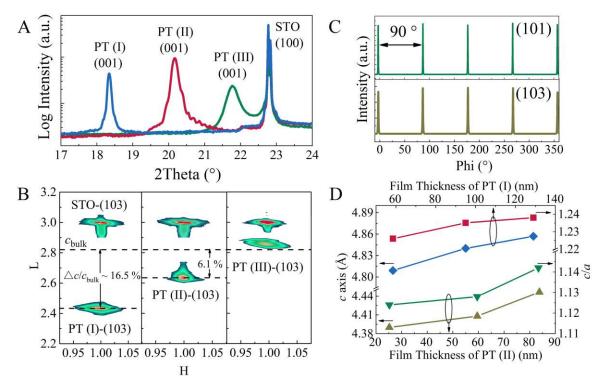


Fig. 1. Crystal structure characterization of epitaxial composite films. (A) Out-of-plane XRD of (001) peaks of PT (I), PT (II), and PT (III) epitaxial thin films on (100) STO substrates. (B) Synchrotron-based (103) X-ray RSM study of PT (I), PT (II), and PT (III) epitaxial thin films about the STO (103) diffraction condition. (C) The phi scans of both (101) and (103) planes of PT (I), demonstrating four-axis symmetric structure. (D) The lattice parameters of *c* and *c/a* of PT (I) and PT (II) as a function of thickness. The original data come from Table S1.

PbTiO<sub>3</sub> has a tetragonal perovskite structure with lattice parameters a = 3.899 Å, c = 4.154 Å, and c/a of 1.065 (Fig. 2A) (20). The precursor of PbO, which is used to prepare PbTiO<sub>3</sub>, has a similar tetragonal structure, but with a large c/a ratio (a = 3.9729 Å, c = 5.0217 Å, c/a = 1.264) (Fig. 2B) (21). The perovskite-like periodic configuration can be identified in the plate-like PbO as marked by the red rectangular frame in Fig. 2B. The similarity in structure between the

PbTiO<sub>3</sub> and PbO configurations offers the potential for realizing the heteroepitaxial growth with interphase strain. Experimentally, in order to obtain such self-assembled heteroepitaxial composite films of the stretched PbTiO<sub>3</sub> with the compressed PbO, the atomic deposition rate has been controlled effectively for their different growth kinetics. Primarily, the Pb-rich composition determined by chemical analysis (ICP-OES) is uniform throughout the films detected by Auger electron spectroscopy with depth analysis (Fig. 2C), except for the higher Pb concentration on the surface. This verifies the homogeneous and randomly alternate growth of PbTiO<sub>3</sub> and PbO in both PT (I) and PT (II) (fig. S3). The dashed circles of Fig. 2D highlight different lattice configuration and contrast with their surroundings. The fast Fourier transform (FFT) pattern taken from a typical example of the regions marked by the dashed circles features a tetragonal structure but with an extinction of (100) plane. It reveals that these regions are PbO (Fig. 2F). However, the other surrounding regions provide a typical FFT pattern for the supertetragonal PbTiO<sub>3</sub> structure (Fig. 2E). The results indicate that the metastable PbO is randomly distributed in PbTiO<sub>3</sub>. The direct evidence for the heteroepitaxial structure between PbTiO<sub>3</sub> and PbO in the present PT (I) is provided by the spherical aberration-corrected high-angle annulardark-field (HAADF) Z-contrast scanning transmission electron microscope (STEM) image (Fig. 2G). The bright, light grey, and dark grey contrast spots correspond to Pb (Z = 82, where Z is the atomic number), Sr (Z = 38), and Ti (Z = 22) columns, respectively, which is approximately proportional to  $Z^2$  (6,22). The intensity profile along the red dashed line in Fig. 2H reveals a transition from Ti of PbTiO<sub>3</sub> to Pb of PbO, indicating a good lattice matching at the PbTiO<sub>3</sub>/PbO interface (Fig. 2I). Both PbTiO<sub>3</sub> and PbO in PT (I) have the same c lattice parameter (4.840 Å) (Fig. 1 and 2G). Hence, in the present PT (I) epitaxial thin films PbO suffers a small out-of-plane compression strain of 3.6 %, while a giant tensile strain (16.5 %) for PbTiO<sub>3</sub> (Fig. 1B). It is

worth noting that the defect dipole generated in such special environment usually cannot produce such giant strain (16).

Investigations employing HAADF-STEM (c/a = 1.224) (Fig. 2) underpin the giant c/a ratio of PbTiO<sub>3</sub> in PT (I) (c/a = 1.238, Table S1) as determined from both macroscopic XRD and synchrotron-based RSM about the (103) plane (Fig. 1B). This c/a value is much larger than that of bulk (1.065), or in any other previously reported results for PbTiO<sub>3</sub> (17). It is comparable to that of the super-tetragonal phases that appear in the biaxial-strained BiFeO<sub>3</sub> films (1.232) and in those perovskite compounds synthesized by high-pressure and high-temperature methods, such as PbVO<sub>3</sub> (1.229), and BiCoO<sub>3</sub> (1.267) (10-12).

Intriguingly, the *c/a* ratio can be adjusted by controlling the oxygen ratio during the growth of thin films. For example, the sample PT (II) was prepared with 9 % oxygen, which features not only smaller *c/a* (1.142) but also lower Pb concentration than PT (I) (ICP-OES analysis in Materials and Methods, Fig. 1, fig. S3, and fig. S4). Therefore, the oxygen ratio affects the Pb atomic deposition rate of the PbTiO<sub>3</sub> epitaxial composite thin films. To grow the present super-tetragonal films, an atmosphere with deficient oxygen is required for fast PbO nucleation. The volume fractions of PbTiO<sub>3</sub> and PbO are 100/0, 80/20, and 45.3/54.7 for the PT (III), PT (II) and PT (I) thin films, respectively. The amount of PbO in the present films determines the *c/a* ratio, which further reveals the role of PbO in interphase strain (fig. S22). It is important to note that unlike the studies that introduce biaxial strain, the present method of interphase strain has little dependence of substrates. Super-tetragonal films such as PT (I) can also be successfully obtained on other lattice-mismatched substrates, such as inexpensive LaAlO<sub>3</sub> or sapphire, indicating it is distinctly irrelevant to substrate biaxial strain from both Poisson and electrostriction effects ( Detailed discussion in Table S1 and fig. S5 and S6).

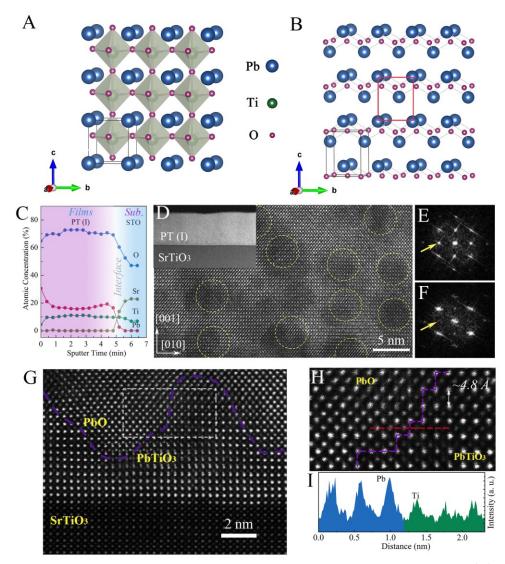


Fig. 2. Atomic resolution microstructure of epitaxial composite films. (A) Crystalline structure of PbTiO<sub>3</sub>. (B) Crystalline structure of PbO. (C) Atomic concentration depth analysis by Auger electron spectroscopy of the PT (I) thin films. (D) High-resolution transmission electron microscopy image along the a-

axis of the PT (I) thin films, which underpins the epitaxial growth and a single set of tetragonal lattice parameters. The inset displays the low-magnification cross-section image. The regions indicated by the yellow dashed circles represent PbO. (E) The fast Fourier transform (FFT) pattern taken from the regions surrounding the yellow dashed circles, featuring the  $PbTiO_3$ 

structure. (**F**) The FFT pattern taken from a typical example of the regions marked by yellow dashed circles, indicating the PbO structure. (**G**) HAADF-STEM image of the heteroepitaxial interface between PbTiO<sub>3</sub> and PbO viewed along the *a* axis of the PT (I) thin film. It also demonstrates that PbTiO<sub>3</sub> firstly grew on the substrate. The detailed discussion of the interface between film and substrate is in fig. S6. (**H**) Enlarged view of the white rectangle in **G**, verifying that PbTiO<sub>3</sub> and PbO have the same lattice parameters. (**I**) Intensity profile along the red dashed line in **H**, directly revealing the transition from Ti to Pb.

To further characterize the interface between PbTiO<sub>3</sub> and PbO, we carried out first-principles calculations. To model this system we used a number of infinitely extended layers of PbTiO<sub>3</sub> matched to an equal number of infinitely extended layers of PbO for four possible sets of planes: (100), (110), (101), and (001). For the (100) case we did this for groups that included 3, 5, and 7 layers containing Pb. For the (110) and (101) cases we used 6 and 10 layers (Fig. 3A). For the (001) case we used 3 and 5 layers. In all cases the atomic configurations were fully relaxed until the forces between atoms were below 0.01 eV/Å, and the stresses on the cell were below 0.01 GPa. As depicted in Fig. 3B, the calculations of *c/a* ratio, lattice parameters and displacement of Ti atom ( $\delta z_{Ti}$ ) with respect to the center of the cage of surrounding Pb atoms are converged well with increasing number of layers. For the (100), (110), and (101) interfaces the *c/a* ratio is around 1.22, in excellent agreement with the experimental result; even for the (001) interface, *c/a* is almost 1.2. The results theoretically prove the particular concept of interphase strain.

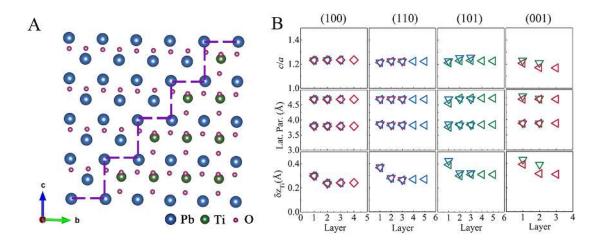


Fig. 3. Calculations of PbTiO<sub>3</sub>/PbO interfaces. (A) Example of PbTiO<sub>3</sub>/PbO system in our calculations (periodic boundary conditions apply): PbTiO<sub>3</sub>/PbO (101) interface (purple dashed line), viewed along the *a* axis. (B) Structural results of density-functional theory calculations of four different PbTiO<sub>3</sub>/PbO interfaces. Top row: tetragonal c/a ratio; middle row: *c* and *a* lattice parameters; bottom row: spontaneous polarization  $\delta z_{Ti}$ .

A giant *c/a* ratio is normally associated with a large polarization in perovskite oxides. The ferroelectric hysteresis loops feature a remanent polarization (*P*<sub>r</sub>) of PT (I) as large as 236.3  $\mu$ C/cm<sup>2</sup> (Fig. 4A). Intriguingly, the present polarization of PT (I) is the highest one ever reported for ferroelectrics (Fig. 4B) (*10*,*23-25*). For example, it is 1.8 times as large as that of the tetragonal-like BiFeO<sub>3</sub> epitaxial thin films (130  $\mu$ C/cm<sup>2</sup>) and 3.4 times of that of the strained BaTiO<sub>3</sub> thin films (70  $\mu$ C/cm<sup>2</sup>) (*10*,*25*). It is also much larger than those calculated spontaneous polarization values of Pb or Bi based perovskites with large *c/a* ratio, such as PbVO<sub>3</sub> (179  $\mu$ C/cm<sup>2</sup>) and BiCoO<sub>3</sub> (152  $\mu$ C/cm<sup>2</sup>) (*26*). The nature of the giant polarization can also be directly revealed by the large  $\delta_{Ti}$  as displayed in fig. S6 (*17*,*27*). In PT (I), the STEM result for the  $\delta_{TTi}$  value is 0.474 Å, almost three times as for bulk PbTiO<sub>3</sub> (0.162 Å) (*28*), which directly reveals the crystallographic character of giant spontaneous polarization. Furthermore, the  $\delta_{TTi}$  value of first-principles calculations in some cases at the interface gets close to the one found experimentally (Fig. 3B). Hence, there is very likely a strong electrostatic interaction at the phase

boundary of the ferroelectric/paraelectric interfaces between PbTiO<sub>3</sub> and PbO (29), resulting in the strong polarization. In the PT (II) thin films a large  $P_r$  (129.6  $\mu$ C/cm<sup>2</sup>) was also observed (fig. S7). A linear correlation between  $P_r$  and c/a has been found in the top left inset of Fig. 4A. The ferroelectricity of PT (I) is supported by piezoelectric measurements (the bottom right inset of Fig. 4A). The relative yellow (1  $\mu$ m square) and pink (3  $\mu$ m square) contrasts indicate the upward (-10 V) and downward (+10 V) polarization states, respectively. The domain pattern after switching clearly underpins the intrinsic nature of ferroelectricity in PT (I). Local piezoresponse amplitude and phase curves demonstrate apparent ferroelectric switching (fig. S7).

Note that the existence of PbO contributes little to the polarization (fig. S8-S11), the PT (I) thin films show negligible leakage current (fig. S12), and the giant polarization phenomenon has been observed in abundant samples. The tilted hysteresis loop is suggested to be related to the continuous multilevel switching in such composite of ferroelectric PbTiO<sub>3</sub> and dielectric PbO. Similar phenomenon with multi-step polarization process be also caused by the switching hindering effect related to the ferroelastic-ferroelectric coupling (30). The facts of occasionally observed multi-step polarization process and the stable shape of the hysteresis loop as a function of temperature or frequency imply the intrinsic ferroelectricity of the present thin films, which is different to electrets (Detailed discussions in Supplementary Text, fig. S13-S16).

Temperature-dependent XRD was performed to determine the ferroelectric phase stability of the present films. As depicted in Fig. 4C, the ferroelectric phase of PT (I) is stable up to 725 °C, compared with the  $T_C$  (490 °C) of bulk PbTiO<sub>3</sub> (20). PT (I) exhibits the highest temperature for ferroelectric phase in all reported PbTiO<sub>3</sub> studies. According to the Landau-Ginzburg-Devonshire (LGD) theory (17), if the crystal structure could be more stable against temperature, its ferroelectric-to-paraelectric phase transition (~1000 °C) could be even higher in the PT(I) thin

films which have giant c/a and polarization. The cyclic curves reveal a stable tetragonal structure for PT (I) if temperatures up to 650 °C (fig. S18B). In the tetragonal phase, the *c* axis of PT (I) features a similar positive thermal expansion to that of PbO, which indicates that PbO determines the thermal expansion of PbTiO<sub>3</sub> (Table S2). At temperatures higher than 725 °C, irreversible structural transformation occurs, in which the *c* axis of PT (I) collapses from the large value of 4.92 Å to the normal value of 3.98 Å in the PT (III). At the same time, the excess PbO is isolated from the lattice of PbTiO<sub>3</sub> as a second phase (fig. S19). A huge volume contraction (19 %) occurs at the structure collapse temperature in PT (I), which has never been observed in negative thermal expansion materials. As a comparison, the largest volume contraction ever reported is 2.6 % for BiNiO<sub>3</sub> and it is 1 % for LaCu<sub>3</sub>Fe<sub>4</sub>O<sub>12</sub> (*31*). Such huge volume contraction in the present PT (I) should be originated from the role of spontaneous volume ferroelectrostriction (SVFS) (*31*), in which giant spontaneous polarization will produce a large ferroelectric volume. Thus a large volume contraction occurs during the collapse process with the loss of ferroelectricity.

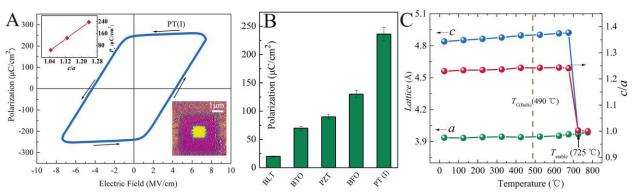
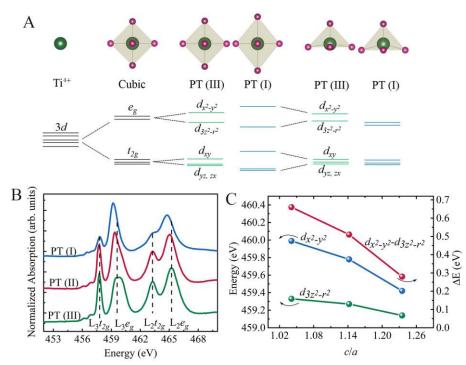


Fig. 4. Giant ferroelectric polarization and enhanced ferroelectric temperature in the PT (I) epitaxial composite films. (A) Ferroelectric hysteresis loop of the PT (I) thin films with a thickness of 129 nm grown on 0.7 wt % Nb-doped STO with Pt top electrode. The top left inset depicts the remanent polarization as a function of c/a. The bottom right inset displays out-of-

plane phase image after a box-in-box switching with a tip bias of ±10 V in the PT (I) thin films with a thickness of 38 nm by piezoresponse force microscopy. (**B**) Comparison of polarization of the present PT (I) thin films with the previously experimentally measured  $P_r$  in films from left to right: Bi<sub>3.25</sub>La<sub>0.75</sub>Ti<sub>3</sub>O<sub>12</sub> (BLT) (*23*), strained BaTiO<sub>3</sub> (BTO) (*24*), unstrained Pb(Zr<sub>0.2</sub>Ti<sub>0.8</sub>)O<sub>3</sub> (PZT) (*25*), and strained BiFeO<sub>3</sub> (BFO) (*10*). (**C**) Temperature dependence of lattice parameters and *c/a* of PT (I). The position of  $T_c$  of bulk PbTiO<sub>3</sub> is indicated by the dotted line for comparison.

In order to elucidate the mechanism of the giant ferroelectric polarization in PT (I), we have studied its electronic hybridization using X-ray absorption spectroscopy (XAS). The electronic state of the 3d levels is highlighted in Fig. 5A. On the basis of crystal field theory, the fivefold degenerated 3*d* level splits into doublet  $e_g$  and triplet  $t_{2g}$  levels in the octahedral symmetry (32). In the tetragonal symmetry,  $e_g(t_{2g})$  levels should be split into  $d_{x^2-y^2}$  and  $d_{3z^2-r^2}(d_{xy})$  and  $d_{yz, zx}$ orbitals. A larger c/a would generate a larger splitting. For tetragonal ferroelectrics, the Ti<sup>4+</sup> transition metal ions shift along an apical direction, which brings in the higher *c*-axis orbital  $(d_{3z^2-r^2} \text{ and } d_{yz, zx})$  and lower in-plane orbital  $(d_{x^2-y^2} \text{ and } d_{xy})$ . Hence the splitting between  $d_{x^2-y^2}$ and  $d_{3z^2-r^2}$  ( $d_{xy}$  and  $d_{yz, zx}$ ) orbitals will be weakened. The splitting of  $L_3 e_g$  peaks becomes smaller from PT (III) to PT (I) as provided in Fig. 5B. Both the energy of  $d_{x^2-y^2}$  and  $d_{3z^2-r^2}$  orbitals decreases with increasing c/a, while the  $\Delta E (d_{x^2-y^2}-d_{3z^2-r^2})$  also reduces from 0.66 eV to 0.28 eV (Fig. 5C). As discussed above, the weakened splitting of  $e_g$  in PT (I) with enhanced c/a indicates larger Ti<sup>4+</sup> distortion (off-center displacement), resulting in the giant ferroelectric polarization. Furthermore, both the decrease in the energy difference between the two main peaks of the  $L_3$  or  $L_2$  edges and the lower intensity of  $L_3 t_{2g}$  or  $L_2 t_{2g}$  indicate the enhanced ionic distortion and the existence of Ti<sup>3+</sup> ions in the PT (I) thin films. This is in good agreement with O K-edge XAS and XPS (fig. S20 and S21). The existence of Ti<sup>3+</sup> ions would cause additional imperfection in the crystal with increasing distortions and also enhance the polarization (fig. S21).



**Fig. 5 Electronic hybridization analysis.** (A) Schematic diagram of local structures of the transition metal Ti oxide, and the 3*d* level splits in the spherical, oxygen octahedral, tetragonal and polar tetragonal site symmetries for the PT (I) and PT (III) thin films. (B) Ti  $L_{2,3}$ -edge X-ray absorption spectroscopy measurements of PT (I), PT (II), and PT (III) thin films. (C) Energy of  $d_{x^2-y^2}$  and  $d_{3z^2-r^2}$  peaks of  $L_3 e_g$  orbitals as a function of c/a.

In summary, this study unveils the unprecedented giant remanent polarization (236.3  $\mu$ C/cm<sup>2</sup>) and much enhanced stable temperature (725 °C) in super-tetragonal PbTiO<sub>3</sub> ferroelectrics through the process of interphase strain. The STEM results revealed the intrinsic microstructure of heteroepitaxial interphase between PbTiO<sub>3</sub> and PbO. The giant polarization was confirmed by both the STEM and XAS measurements, which originates from large off-center ionic displacements. The density-functional theory calculations verify the large *c/a* ratios for various PbTiO<sub>3</sub>/PbO interfaces that are very similar to the ones obtained experimentally. We conclude by stressing some advantages of the present method, which could create a new pathway for material design: i. The interphase strain can provide not only isotropic tensile strain but also isotropic

compressive strain; ii. The level of strain can be modulated by adjusting the composition (fig. S22); iii. The achievement of strain in thin films can be free from the choice of substrates.

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## **Supplementary Materials:**

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